

**7A, 100V, 0.300 Ohm, N-Channel, Logic Level, Power MOSFETs**

These N-Channel power MOSFETs are manufactured using a modern process. This process, which uses feature sizes approaching those of LSI integrated circuits gives optimum utilization of silicon, resulting in outstanding performance. They were designed for use in applications such as switching regulators, switching converters, motor drivers, relay drivers and emitter switches for bipolar transistors. This performance is accomplished through a special gate oxide design which provides full rated conductance at gate bias in the 3V to 5V range, thereby facilitating true on-off power control directly from logic level (5V) integrated circuits.

Formerly developmental type TA49046.

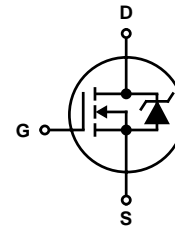
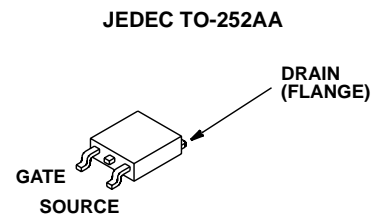
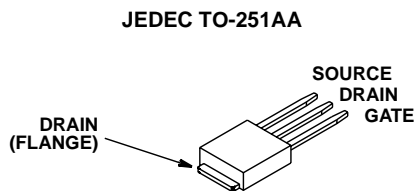
**Ordering Information**

PART NUMBER	PACKAGE	BRAND
RFD7N10LE	TO-251AA	7N10L
RFD7N10LESM	TO-252AA	7N10LE

NOTE: When ordering, use the entire part number. Add suffix 9A to obtain the TO-252AA variant in the tape and reel, i.e., RFD7N10LESM9A.

**Features**

- 7A, 100V
- $r_{DS(ON)} = 0.300\Omega$
- Temperature Compensating PSPICE® Model
- Can be Driven Directly from CMOS, NMOS, TTL Circuits
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- 175°C Operating Temperature
- Related Literature
  - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

**Symbol**

**Packaging**


# RFD7N10LE, RFD7N10LESM

## Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

	RFD7N10LE, RFD7N10LESM	UNITS
Drain to Source Voltage . . . . .	100	V
Drain to Gate Voltage . . . . .	100	V
Gate to Source Voltage . . . . .	+10, -8	V
Drain Current		
Continuous . . . . .	7	A
Pulsed Drain Current . . . . .	Refer to Peak Current Curve	
Pulsed Avalanche Rating . . . . .	Refer to UIS Curve	
Power Dissipation . . . . .	47	W
Derate Above $25^\circ\text{C}$ . . . . .	0.318	$\text{W}/^\circ\text{C}$
Operating and Storage Temperature . . . . .	-55 to 175	$^\circ\text{C}$
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s . . . . .	300	$^\circ\text{C}$
Package Body for 10s, See Techbrief 334 . . . . .	260	$^\circ\text{C}$

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1.  $T_J = 25^\circ\text{C}$  to  $150^\circ\text{C}$ .

## Electrical Specifications $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	$BV_{DSS}$	$I_D = 250\mu\text{A}$ , $V_{GS} = 0\text{V}$	100	-	-	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$ , $I_D = 250\mu\text{A}$	1	-	3	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 95\text{V}$ , $V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{DS} = 90\text{V}$ , $V_{GS} = 0\text{V}$ , $T_C = 150^\circ\text{C}$	-	-	250	$\mu\text{A}$
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS} = +10, -8\text{V}$	-	-	10	$\mu\text{A}$
On Resistance	$r_{DS(ON)}$	$I_D = 7\text{A}$ , $V_{GS} = 5\text{V}$	-	-	0.300	$\Omega$
Turn-On Time	$t_{ON}$	$V_{DD} = 50\text{V}$ , $I_D = 7\text{A}$ $R_L = 7.1\Omega$ , $V_{GS} = 5\text{V}$ $R_{GS} = 2.5\Omega$	-	-	110	ns
Turn-On Delay Time	$t_{d(ON)}$		-	10	-	ns
Rise Time	$t_r$		-	65	-	ns
Turn-Off Delay Time	$t_{d(OFF)}$		-	23	-	ns
Fall Time	$t_f$		-	18	-	ns
Turn-Off Time	$t_{OFF}$		-	-	60	ns
Total Gate Charge	$Q_g(TOT)$	$V_{GS} = 0$ to $10\text{V}$	-	125	150	nC
Gate Charge at 5V	$Q_g(5)$	$V_{GS} = 0$ to $5\text{V}$		67	80	nC
Threshold Gate Charge	$Q_g(TH)$	$V_{GS} = 0$ to $1\text{V}$		3.7	4.5	nC
Input Capacitance	$C_{ISS}$	$V_{DS} = 25\text{V}$ , $V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	360	-	pF
Output Capacitance	$C_{OSS}$		-	70	-	pF
Reverse Transfer Capacitance	$C_{RSS}$		-	20	-	pF
Thermal Resistance Junction to Case	$R_{\theta JC}$		-	-	3.15	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	TO-251 and TO-252 Package	-	-	100	$^\circ\text{C}/\text{W}$

## Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	$V_{SD}$	$I_{SD} = 7\text{A}$	-	-	1.5	V
Reverse Recovery Time	$t_{rr}$	$I_{SD} = 7\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	130	ns

Typical Performance Curves Unless Otherwise Specified

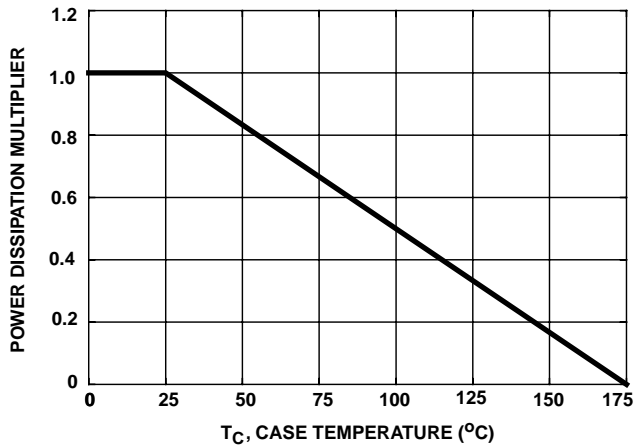


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

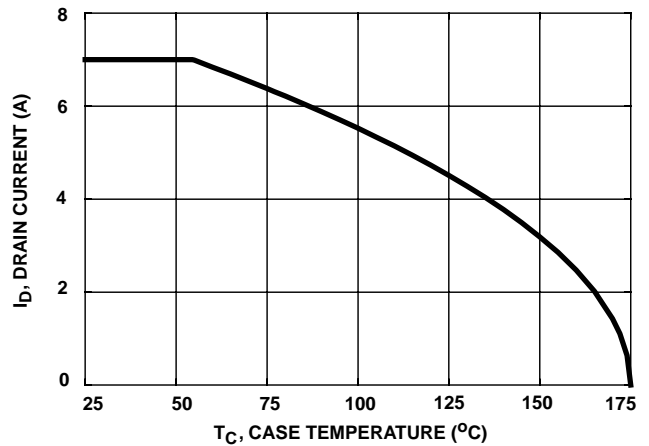


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

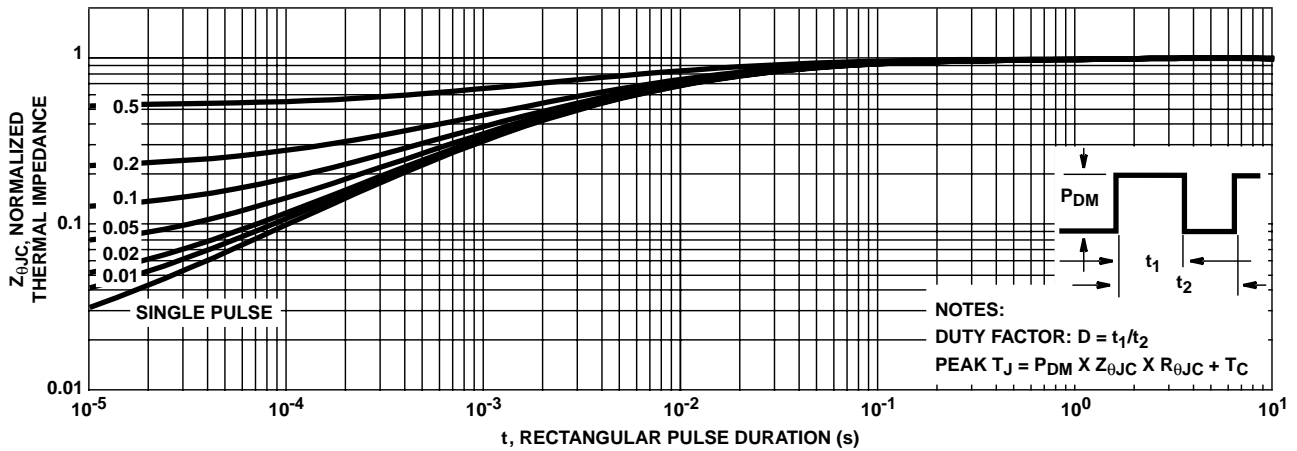


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

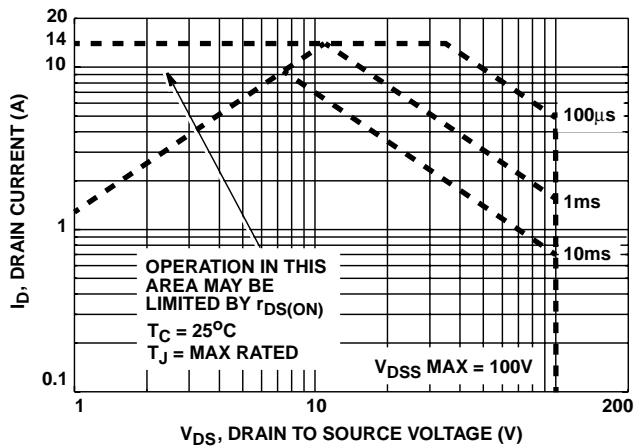


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

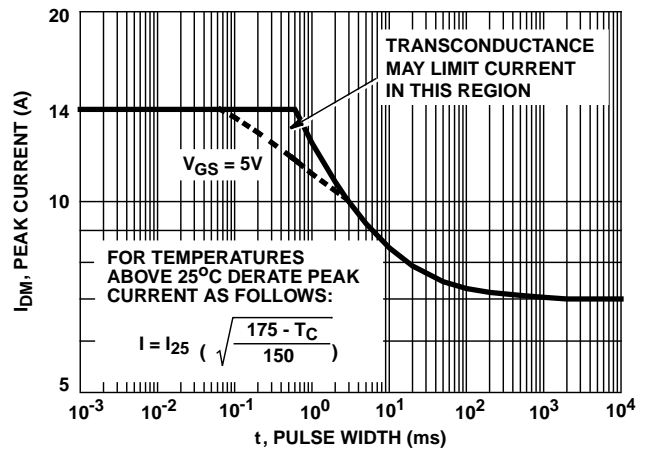


FIGURE 5. PEAK CURRENT CAPABILITY

Typical Performance Curves Unless Otherwise Specified (Continued)

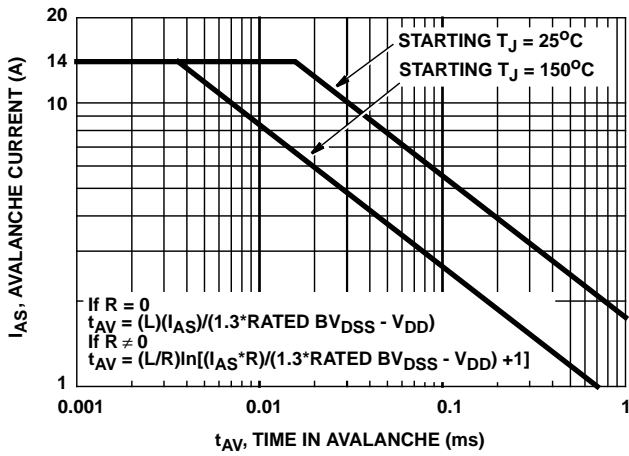


FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING

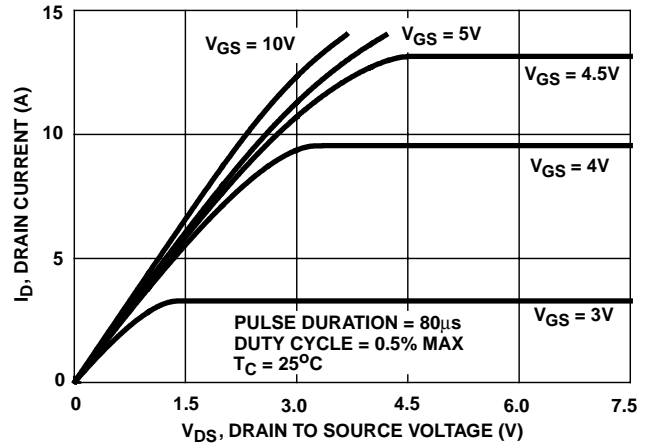


FIGURE 7. SATURATION CHARACTERISTICS

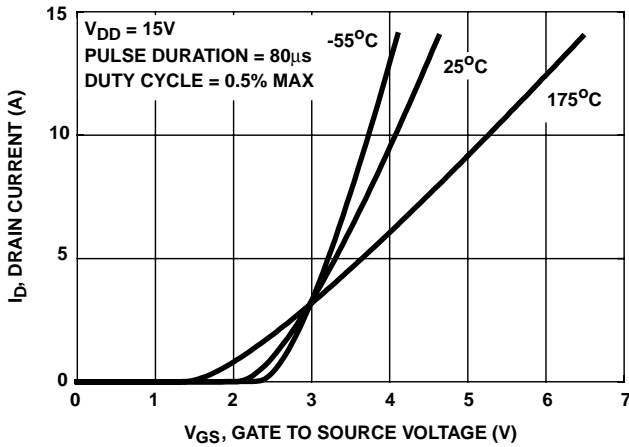


FIGURE 8. TRANSFER CHARACTERISTICS

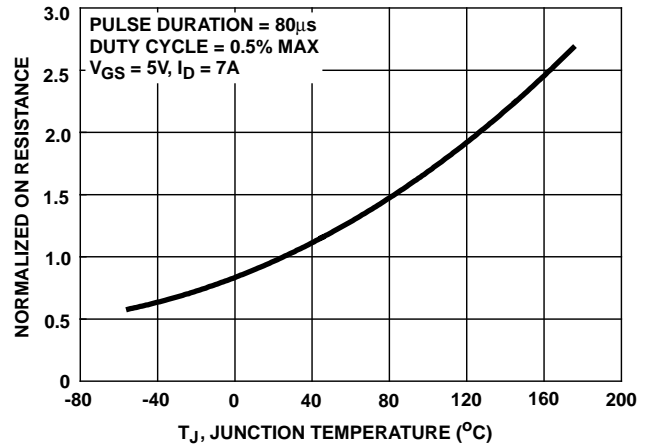


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

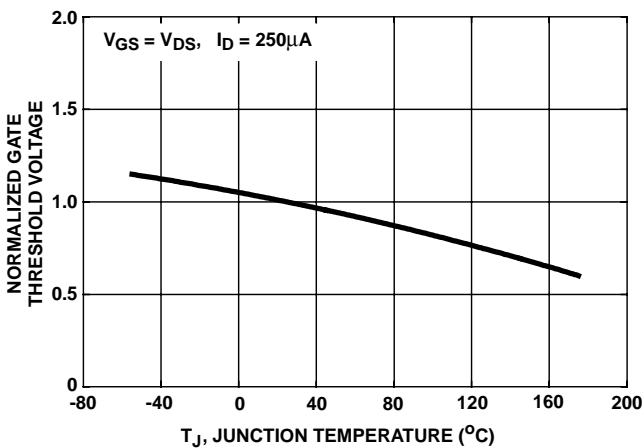


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

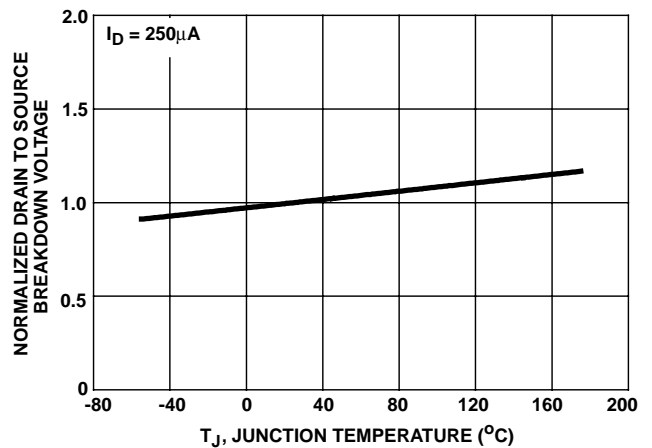


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

Typical Performance Curves Unless Otherwise Specified (Continued)

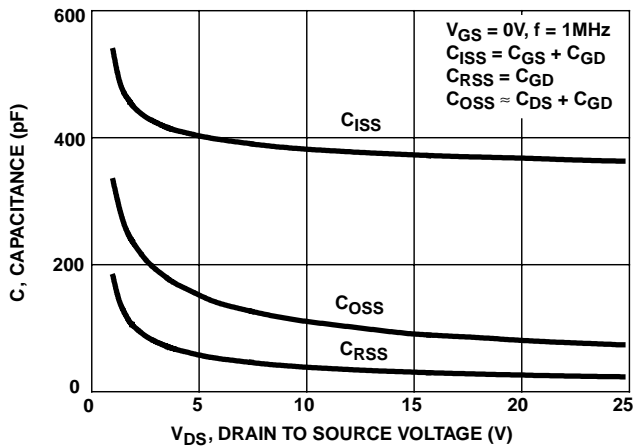
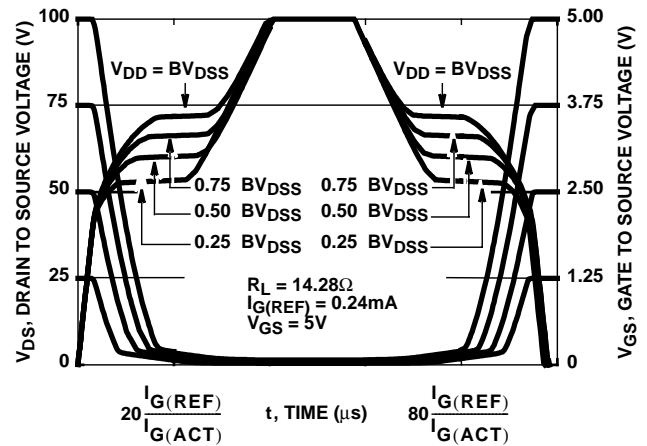


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Intersil Application Notes AN7254 and AN7260.

FIGURE 13. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

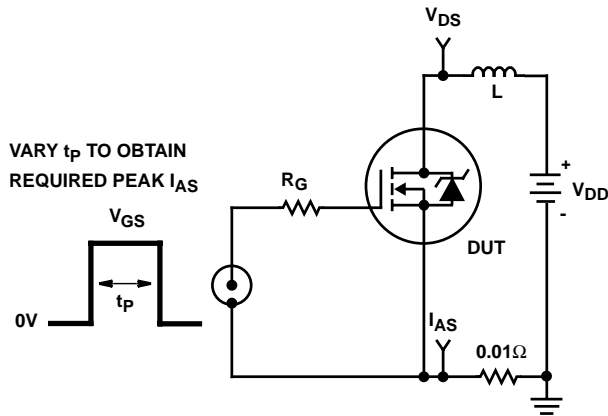


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

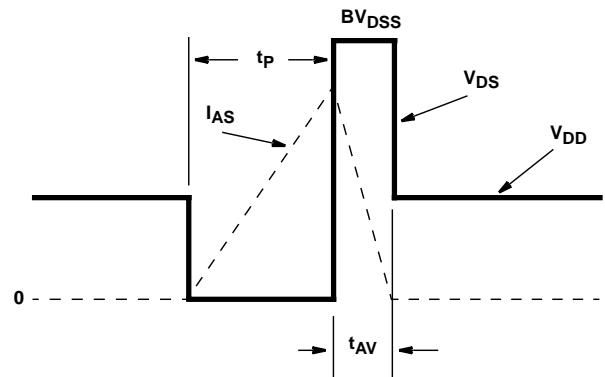


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

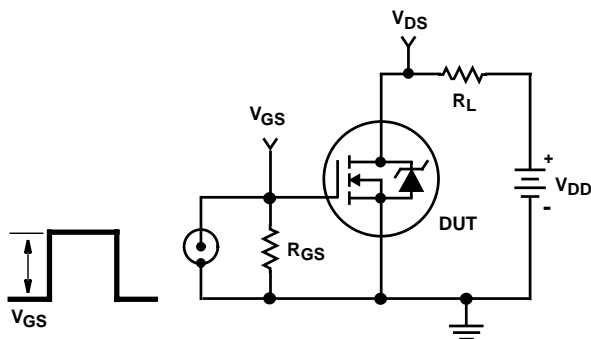


FIGURE 16. RESISTIVE SWITCHING TEST CIRCUIT

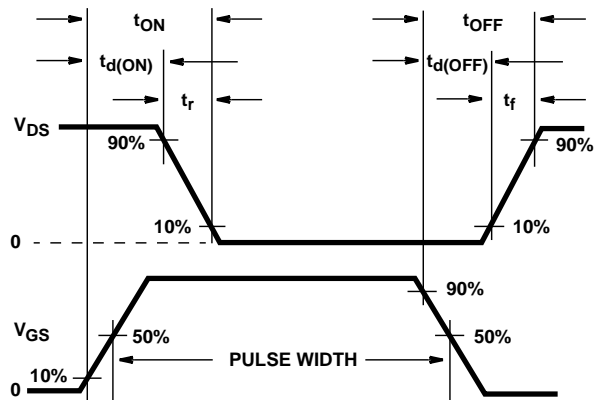


FIGURE 17. RESISTIVE SWITCHING WAVEFORMS

# RFD7N10LE, RFD7N10LESM

## PSPICE Electrical Model

SUBCKT RFD7N10LE 2 1 3; rev 6/2/93

CA 12 8 7.5e-10  
 CB 15 14 7.6e-10  
 CIN 6 8 4.03e-10

DBODY 7 5 DBODYMOD  
 DBREAK 5 11 DBREAKMOD  
 DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 116.7  
 EDS 14 8 5 8 1  
 EGS 13 8 6 8 1  
 ESG 6 10 6 8 1  
 EVTHRES 6 21 19 8 1  
 EVTEMP 20 6 18 22 1

IT 8 17 1

LDRAIN 2 5 1e-9  
 LGATE 1 9 3.7e-9  
 LSOURCE 3 7 3.4e-9

MMED 16 6 8 8 MMEDMOD  
 MSTRO 16 6 8 8 MSTROMOD  
 MWEAK 16 21 8 8 MWEAKMOD

RBREAK 17 18 RBREAKMOD 1  
 RDRAIN 50 16 RDRAINMOD 9.4e-2  
 RGATE 9 20 3.3  
 RLDRAIN 2 5 10  
 RLGATE 1 9 37  
 RLSOURCE 3 7 34  
 RSLC1 5 51 RSLCMOD 1e-6  
 RSLC2 5 50 1e3  
 RSOURCE 8 7 RSOURCEMOD 1.3e-2  
 RVTHRES 22 8 RVTHRESMOD 1  
 RVTEMP 18 19 RVTEMPMOD 1

S1A 6 12 13 8 S1AMOD  
 S1B 13 12 13 8 S1BMOD  
 S2A 6 15 14 13 S2AMOD  
 S2B 13 15 14 13 S2BMOD

VBAT 22 19 DC 1

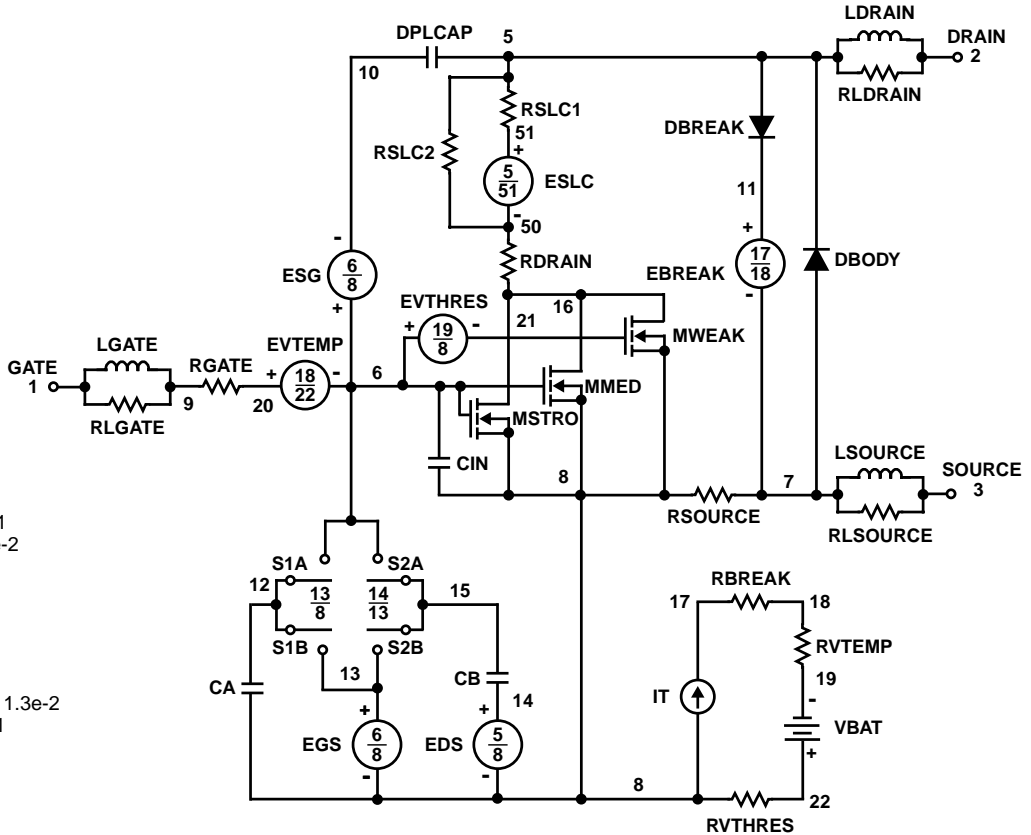
ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))\*(PWR(V(5,51))/(1e-6\*17.3),3.5)}

.MODEL DBODYMOD D (IS = 1.2e-12 RS = 1.2e-2 TRS1 = 1.2e-3 TRS2 = 1.03e-6 CJO = 6.7e-10 TT = 6.9e-8 M = 0.77)  
 .MODEL DBREAKMOD D (RS = 9.9e-1 TRS1 = 1e-3 TRS2 = -2e-5)  
 .MODEL DPLCAPMOD D (CJO = 4.3e-10 IS = 1e-30 M = 0.9 N = 10)  
 .MODEL MMEDMOD NMOS (VTO = 1.88 KP = 5 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 3.3)  
 .MODEL MSTROMOD NMOS (VTO = 2.13 KP = 12.4 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u)  
 .MODEL MWEAKMOD NMOS (VTO = 1.59 KP = 0.12 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 33 RS = 0.1)  
 .MODEL RBREAKMOD RES (TC1 = 1.05e-3 TC2 = -5e-7)  
 .MODEL RDRAINMOD RES (TC1 = 8.1e-3 TC2 = 2.4e-5)  
 .MODEL RSLCMOD RES (TC1 = 3e-3 TC2 = 2e-6)  
 .MODEL RSOURCEMOD RES (TC1 = 1e-3 TC2 = 1e-6)  
 .MODEL RVTHRESMOD RES (TC1 = -1.5e-3 TC2 = -4.3e-6)  
 .MODEL RVTEMPMOD RES (TC1 = -1.6e-3 TC2 = 1.5e-6)

.MODEL S1AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -4.5 VOFF = -2.5)  
 .MODEL S1BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -2.5 VOFF = -4.5)  
 .MODEL S2AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -0.3 VOFF = 0.2)  
 .MODEL S2BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 0.2 VOFF = -0.3)

.ENDS

NOTE: For further discussion of the PSPICE model consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options; IEEE Power Electronics Specialist Conference Records 1991.



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